

<b>Notice of References Cited</b>	Application/Control No. <b>09/737,243</b>	Applicant(s)/Patent Under Reexam <b>Chris M. Pavlakos</b>	
	Examiner <b>Melur. Ramakrishnaiah</b>	Art Unit <b>2643</b>	Page 1 of 1

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	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
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	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Country	Name	Classification <sup>2</sup>	
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**NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
U	Sarel et al. ; A system and method ... self testing ... of subjects; 1-22-1998, WO 98/02083    ←
V	
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\* A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).    <sup>1</sup> Dates in MM-YYYY format are publication dates.    <sup>2</sup> Classifications may be U.S. or foreign.